IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

For:	SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE WITH ENHANCED RESISTANCE TO ELECTROSTATIC BREAKDOWN))))	
Filed:	August 18, 2003))	Examiner: Unassigned
Applic	eation No.: Unassigned))	Group Art Unit: Unassigned
Noriak	ti HIRAGA))	
In re A	application of:)	

Commissioner for Patents
U.S. Patent and Trademark Office
2011 South Clark Place
Customer Window, MS Patent Application
Crystal Plaza Two, Lobby, Room 1B03
Arlington, VA 22202

REQUEST FOR APPROVAL OF DRAWING CHANGES

Sir:

Subject to the approval of the Examiner, it is respectfully requested that Figs. 2A, 2B, 4A, 4B, 5A, 5B and 6 be substituted with the corresponding figures of the attached substitute four (4) drawing sheets including seven (7) figures..

It is respectfully submitted that these changes introduce no new matter as they conform to the specification and/or drawings as originally filed, pursuant to 37 C.F.R. §1.81(d).

Respectfully submitted,

MORGAN, LEWIS & BOCKIUS LLP

Date: August 18, 2003

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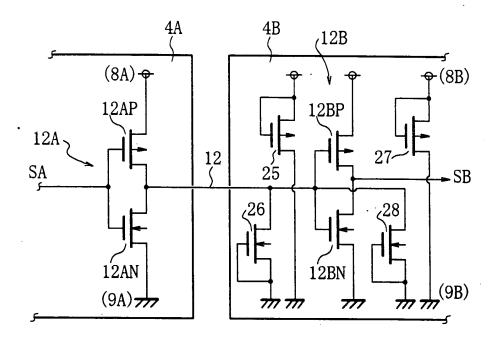


Fig. 2A

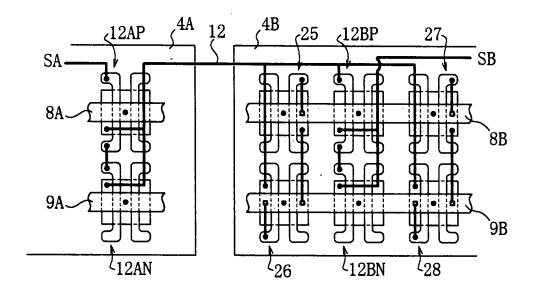


Fig. 2B

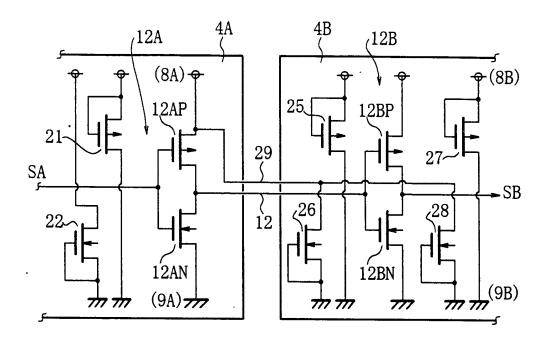


Fig. 4A

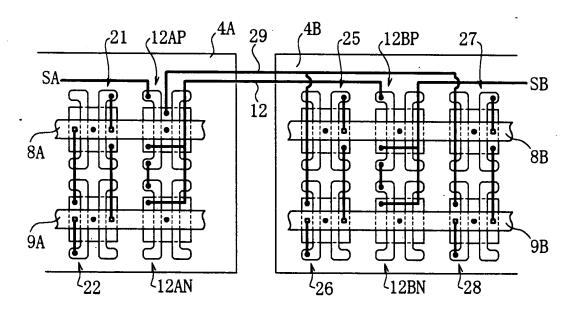


Fig. 4B

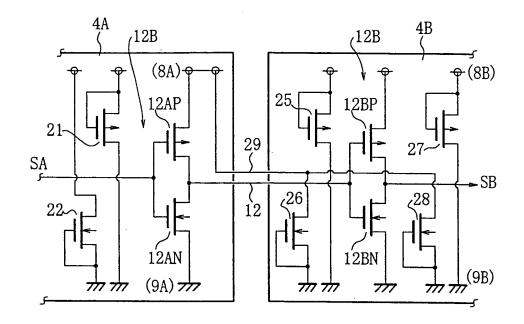


Fig. 5A

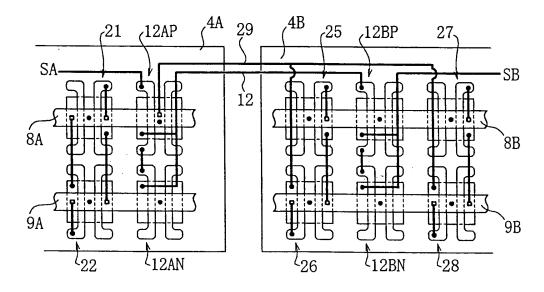


Fig. 5B

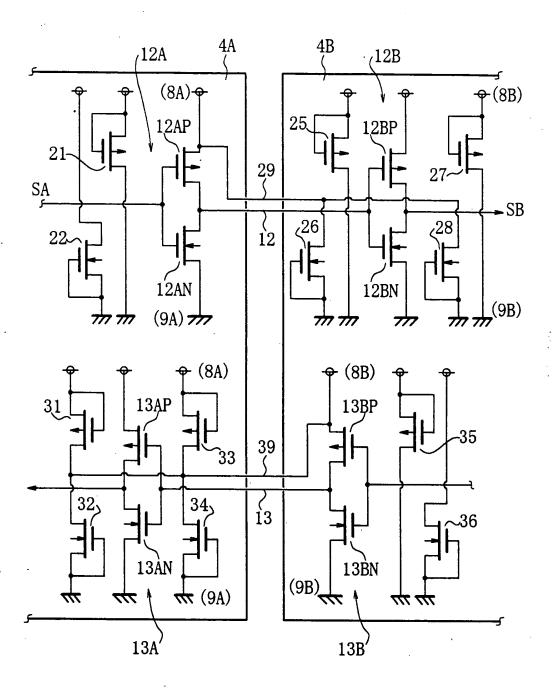


Fig. 6